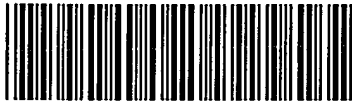


Search Notes

Application/Control No.

10/623,880

Examiner

Young J. Kim

Applicant(s)/Patent under
Reexamination

BARNETT ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
SEQ ID NO: 1 and 27 searched by STIC. ISearched interference patent database.	1/5/2006	YJK